

**Notice of References Cited**

Application/Control No.

10/019,444

Applicant(s)/Patent Under  
Reexamination  
HIRAMATSU ET AL.

Examiner

Leonid M Fastovsky

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6518548	02-2003	Sugaya et al	219/444.1
	B	US-6399926	06-2002	Takano et al	219/497
	C	US-6359264	03-2002	Schaper et al	219/444.1
	D	US-6229116	05-2001	Shirakawa et al	219/290
	E	US-6228171	05-2001	Shirakawa	118/666
	F	US-5998767	12-1999	Kersch et al	219/390
	G	US-2001/0025795	10-2001	Takano et al	204/491
	H	US-5001328	03-1991	Schreder et al	219/447.1
	I	US-4962297	10-1990	Lowenberg	219/448.1
	J	US-3930914	01-1976	Hetrich	156/16
	K	US-6087632	07-2000	Mizosaki et al	219/390
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB2225920	06-1990	Great Britain	Goodchild et al	H05B 1/02
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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